



Attention: Mail Stop AF
Response Under 37 C.F.R. § 1.116
Expedited Procedure Requested
Examining Group 2823

PATENT
Customer No. 22,852
Attorney Docket No. 04329.2335

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Tokuhiwa OHIWA, et al.

Serial No.: 09/604,724

Filed: June 28, 2000

For: HIGH PRECISION PATTERN
FORMING METHOD OF
MANUFACTURING A
SEMICONDUCTOR DEVICE (AS
AMENDED)

Group Art Unit: 2823

Examiner: Maldonado, Julio J.

Amat CMO

9/12/03
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TECHNOLOGY CENTER 2800

MAIL STOP AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

AMENDMENT AFTER FINAL

In reply to the Final Office Action of June 24, 2003, with a period for response extending through September 24, 2003, Applicants propose amending the application as follows, and respectfully request the Examiner's reconsideration in view of remarks that follow:

Amendments to the Claims are reflected in the listing of claims beginning on page 2 of this paper.

Remarks begin on page 9 of this paper.

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